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Understanding <u>Embedded - CPLDs (Complex Programmable Logic Devices)</u>

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	EE PLD
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	6
Number of Macrocells	96
Number of Gates	1800
Number of I/O	68
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7096lc84-7

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Table 2. MAX	7000S Device I	Features -				
Feature	EPM7032S	EPM7064S	EPM7128S	EPM7160S	EPM7192S	EPM7256S
Usable gates	600	1,250	2,500	3,200	3,750	5,000
Macrocells	32	64	128	160	192	256
Logic array blocks	2	4	8	10	12	16
Maximum user I/O pins	36	68	100	104	124	164
t _{PD} (ns)	5	5	6	6	7.5	7.5
t _{SU} (ns)	2.9	2.9	3.4	3.4	4.1	3.9
t _{FSU} (ns)	2.5	2.5	2.5	2.5	3	3
t _{CO1} (ns)	3.2	3.2	4	3.9	4.7	4.7
f _{CNT} (MHz)	175.4	175.4	147.1	149.3	125.0	128.2

...and More Features

- Open-drain output option in MAX 7000S devices
- Programmable macrocell flipflops with individual clear, preset, clock, and clock enable controls
- Programmable power-saving mode for a reduction of over 50% in each macrocell
- Configurable expander product-term distribution, allowing up to 32 product terms per macrocell
- 44 to 208 pins available in plastic J-lead chip carrier (PLCC), ceramic pin-grid array (PGA), plastic quad flat pack (PQFP), power quad flat pack (RQFP), and 1.0-mm thin quad flat pack (TQFP) packages
- Programmable security bit for protection of proprietary designs
- 3.3-V or 5.0-V operation
 - MultiVoltTM I/O interface operation, allowing devices to interface with 3.3-V or 5.0-V devices (MultiVolt I/O operation is not available in 44-pin packages)
 - Pin compatible with low-voltage MAX 7000A and MAX 7000B devices
- Enhanced features available in MAX 7000E and MAX 7000S devices
 - Six pin- or logic-driven output enable signals
 - Two global clock signals with optional inversion
 - Enhanced interconnect resources for improved routability
 - Fast input setup times provided by a dedicated path from I/O pin to macrocell registers
 - Programmable output slew-rate control
- Software design support and automatic place-and-route provided by Altera's development system for Windows-based PCs and Sun SPARCstation, and HP 9000 Series 700/800 workstations

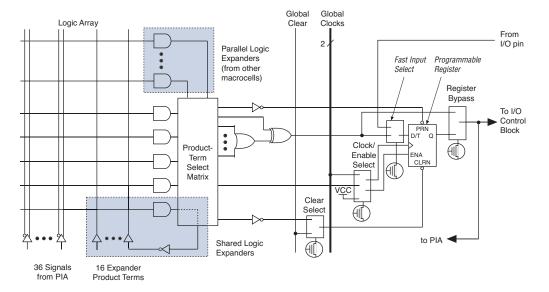
Each LAB is fed by the following signals:

- 36 signals from the PIA that are used for general logic inputs
- Global controls that are used for secondary register functions
- Direct input paths from I/O pins to the registers that are used for fast setup times for MAX 7000E and MAX 7000S devices

Macrocells

The MAX 7000 macrocell can be individually configured for either sequential or combinatorial logic operation. The macrocell consists of three functional blocks: the logic array, the product-term select matrix, and the programmable register. The macrocell of EPM7032, EPM7064, and EPM7096 devices is shown in Figure 3.

Figure 3. EPM7032, EPM7064 & EPM7096 Device Macrocell



Each programmable register can be clocked in three different modes:

- By a global clock signal. This mode achieves the fastest clock-tooutput performance.
- By a global clock signal and enabled by an active-high clock enable. This mode provides an enable on each flipflop while still achieving the fast clock-to-output performance of the global clock.
- By an array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

In EPM7032, EPM7064, and EPM7096 devices, the global clock signal is available from a dedicated clock pin, GCLK1, as shown in Figure 1. In MAX 7000E and MAX 7000S devices, two global clock signals are available. As shown in Figure 2, these global clock signals can be the true or the complement of either of the global clock pins, GCLK1 or GCLK2.

Each register also supports asynchronous preset and clear functions. As shown in Figures 3 and 4, the product-term select matrix allocates product terms to control these operations. Although the product-term-driven preset and clear of the register are active high, active-low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the active-low dedicated global clear pin (GCLRn). Upon power-up, each register in the device will be set to a low state.

All MAX 7000E and MAX 7000S I/O pins have a fast input path to a macrocell register. This dedicated path allows a signal to bypass the PIA and combinatorial logic and be driven to an input D flipflop with an extremely fast (2.5 ns) input setup time.

Expander Product Terms

Although most logic functions can be implemented with the five product terms available in each macrocell, the more complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources; however, the MAX 7000 architecture also allows both shareable and parallel expander product terms ("expanders") that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.



For more information on using the Jam language, refer to AN 122: Using Jam STAPL for ISP & ICR via an Embedded Processor.

The ISP circuitry in MAX 7000S devices is compatible with IEEE Std. 1532 specification. The IEEE Std. 1532 is a standard developed to allow concurrent ISP between multiple PLD vendors.

Programming Sequence

During in-system programming, instructions, addresses, and data are shifted into the MAX 7000S device through the TDI input pin. Data is shifted out through the TDO output pin and compared against the expected data.

Programming a pattern into the device requires the following six ISP stages. A stand-alone verification of a programmed pattern involves only stages 1, 2, 5, and 6.

- Enter ISP. The enter ISP stage ensures that the I/O pins transition smoothly from user mode to ISP mode. The enter ISP stage requires 1 ms.
- 2. *Check ID*. Before any program or verify process, the silicon ID is checked. The time required to read this silicon ID is relatively small compared to the overall programming time.
- 3. *Bulk Erase*. Erasing the device in-system involves shifting in the instructions to erase the device and applying one erase pulse of 100 ms.
- Program. Programming the device in-system involves shifting in the address and data and then applying the programming pulse to program the EEPROM cells. This process is repeated for each EEPROM address.
- Verify. Verifying an Altera device in-system involves shifting in addresses, applying the read pulse to verify the EEPROM cells, and shifting out the data for comparison. This process is repeated for each EEPROM address.
- 6. Exit ISP. An exit ISP stage ensures that the I/O pins transition smoothly from ISP mode to user mode. The exit ISP stage requires 1 ms.

Programmable Speed/Power Control

MAX 7000 devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more, because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000 device for either high-speed (i.e., with the Turbo BitTM option turned on) or low-power (i.e., with the Turbo Bit option turned off) operation. As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder (t_{LPA}) for the t_{LAD} , t_{LAC} , t_{IC} , t_{EN} , and t_{SEXP} , t_{ACL} , and t_{CPPW} parameters.

Output Configuration

MAX 7000 device outputs can be programmed to meet a variety of system-level requirements.

MultiVolt I/O Interface

MAX 7000 devices—except 44-pin devices—support the MultiVolt I/O interface feature, which allows MAX 7000 devices to interface with systems that have differing supply voltages. The 5.0-V devices in all packages can be set for 3.3-V or 5.0-V I/O pin operation. These devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

The VCCINT pins must always be connected to a 5.0-V power supply. With a 5.0-V $V_{\rm CCINT}$ level, input voltage thresholds are at TTL levels, and are therefore compatible with both 3.3-V and 5.0-V inputs.

The VCCIO pins can be connected to either a 3.3-V or a 5.0-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 5.0-V supply, the output levels are compatible with 5.0-V systems. When $V_{\rm CCIO}$ is connected to a 3.3-V supply, the output high is 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with $V_{\rm CCIO}$ levels lower than 4.75 V incur a nominally greater timing delay of $t_{\rm OD2}$ instead of $t_{\rm OD1}$.

Open-Drain Output Option (MAX 7000S Devices Only)

MAX 7000S devices provide an optional open-drain (functionally equivalent to open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. It can also provide an additional wired-OR plane.

By using an external 5.0-V pull-up resistor, output pins on MAX 7000S devices can be set to meet 5.0-V CMOS input voltages. When $V_{\rm CCIO}$ is 3.3 V, setting the open drain option will turn off the output pull-up transistor, allowing the external pull-up resistor to pull the output high enough to meet 5.0-V CMOS input voltages. When $V_{\rm CCIO}$ is 5.0 V, setting the output drain option is not necessary because the pull-up transistor will already turn off when the pin exceeds approximately 3.8 V, allowing the external pull-up resistor to pull the output high enough to meet 5.0-V CMOS input voltages.

Slew-Rate Control

The output buffer for each MAX 7000E and MAX 7000S I/O pin has an adjustable output slew rate that can be configured for low-noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay of 4 to 5 ns. In MAX 7000E devices, when the Turbo Bit is turned off, the slew rate is set for low noise performance. For MAX 7000S devices, each I/O pin has an individual EEPROM bit that controls the slew rate, allowing designers to specify the slew rate on a pin-by-pin basis.

Programming with External Hardware

MAX 7000 devices can be programmed on Windows-based PCs with the Altera Logic Programmer card, the Master Programming Unit (MPU), and the appropriate device adapter. The MPU performs a continuity check to ensure adequate electrical contact between the adapter and the device.



For more information, see the *Altera Programming Hardware Data Sheet*.

The Altera development system can use text- or waveform-format test vectors created with the Text Editor or Waveform Editor to test the programmed device. For added design verification, designers can perform functional testing to compare the functional behavior of a MAX 7000 device with the results of simulation. Moreover, Data I/O, BP Microsystems, and other programming hardware manufacturers also provide programming support for Altera devices.



For more information, see the *Programming Hardware Manufacturers*.

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 7000 devices support JTAG BST circuitry as specified by IEEE Std. 1149.1-1990. Table 9 describes the JTAG instructions supported by the MAX 7000 family. The pin-out tables (see the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin-out information) show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

Table 9. MAX 7000 J	ITAG Instruction	s
JTAG Instruction	Devices	Description
SAMPLE/PRELOAD	EPM7128S EPM7160S EPM7192S	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins.
	EPM7256S	pattern output at the device pins.
EXTEST	EPM7128S EPM7160S EPM7192S EPM7256S	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation.
IDCODE	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
ISP Instructions	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	These instructions are used when programming MAX 7000S devices via the JTAG ports with the MasterBlaster, ByteBlasterMV, BitBlaster download cable, or using a Jam File (.jam), Jam Byte-Code file (.jbc), or Serial Vector Format file (.svf) via an embedded processor or test equipment.

Operating Conditions

Tables 13 through 18 provide information about absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 5.0-V MAX 7000 devices.

Table 1	3. MAX 7000 5.0-V Device Abso	plute Maximum Ratings Note (1)			
Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	Supply voltage	With respect to ground (2)	-2.0	7.0	V
VI	DC input voltage		-2.0	7.0	V
I _{OUT}	DC output current, per pin		-25	25	mA
T _{STG}	Storage temperature	No bias	-65	150	° C
T _{AMB}	Ambient temperature	Under bias	-65	135	° C
TJ	Junction temperature	Ceramic packages, under bias		150	°C
		PQFP and RQFP packages, under bias		135	°C

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CCINT}	Supply voltage for internal logic and input buffers	(3), (4), (5)	4.75 (4.50)	5.25 (5.50)	V
V _{CCIO}	Supply voltage for output drivers, 5.0-V operation	(3), (4)	4.75 (4.50)	5.25 (5.50)	V
	Supply voltage for output drivers, 3.3-V operation	(3), (4), (6)	3.00 (3.00)	3.60 (3.60)	V
V _{CCISP}	Supply voltage during ISP	(7)	4.75	5.25	V
V _I	Input voltage		-0.5 (8)	V _{CCINT} + 0.5	V
Vo	Output voltage		0	V _{CCIO}	V
T _A	Ambient temperature	For commercial use	0	70	°C
		For industrial use	-40	85	°C
TJ	Junction temperature	For commercial use	0	90	°C
V _I II V _O C T _A A		For industrial use	-40	105	° C
t _R	Input rise time			40	ns
t _F	Input fall time			40	ns

Symbol	Parameter	Conditions	Min	Max	Unit
V _{IH}	High-level input voltage		2.0	V _{CCINT} + 0.5	V
V _{IL}	Low-level input voltage		-0.5 (8)	0.8	V
V _{OH}	5.0-V high-level TTL output voltage	I _{OH} = -4 mA DC, V _{CCIO} = 4.75 V (10)	2.4		V
3.	3.3-V high-level TTL output voltage	I _{OH} = -4 mA DC, V _{CCIO} = 3.00 V (10)	2.4		V
	3.3-V high-level CMOS output voltage	$I_{OH} = -0.1 \text{ mA DC}, V_{CCIO} = 3.0 \text{ V} (10)$	V _{CCIO} - 0.2		V
V _{OL}	5.0-V low-level TTL output voltage	I _{OL} = 12 mA DC, V _{CCIO} = 4.75 V (11)		0.45	V
	3.3-V low-level TTL output voltage	I _{OL} = 12 mA DC, V _{CCIO} = 3.00 V (11)		V _{CCINT} + 0.5) 0.8	V
	3.3-V low-level CMOS output voltage	$I_{OL} = 0.1 \text{ mA DC}, V_{CCIO} = 3.0 \text{ V}(11)$		0.2	V
lı	Leakage current of dedicated input pins	$V_I = -0.5 \text{ to } 5.5 \text{ V } (11)$	-10	10	μА
l _{OZ}	I/O pin tri-state output off-state current	$V_I = -0.5 \text{ to } 5.5 \text{ V } (11), (12)$	-40	40	μА

Table 1	6. MAX 7000 5.0-V Device Capa	ncitance: EPM7032, EPM7064 & EPM7	7096 Devices	Note (1	3)
Symbol	Parameter	Conditions	Min	Max	Unit
C _{IN}	Input pin capacitance	V _{IN} = 0 V, f = 1.0 MHz		12	pF
C _{I/O}	I/O pin capacitance	V _{OUT} = 0 V, f = 1.0 MHz		12	pF

Table 1	Table 17. MAX 7000 5.0-V Device Capacitance: MAX 7000E Devices Note (13)						
Symbol	Parameter	Conditions	Min	Max	Unit		
C _{IN}	Input pin capacitance	V _{IN} = 0 V, f = 1.0 MHz		15	pF		
C _{I/O}	I/O pin capacitance	V _{OUT} = 0 V, f = 1.0 MHz		15	pF		

Table 1	Table 18. MAX 7000 5.0-V Device Capacitance: MAX 7000S Devices Note (13)						
Symbol	Parameter	Conditions	Min	Max	Unit		
C _{IN}	Dedicated input pin capacitance	V _{IN} = 0 V, f = 1.0 MHz		10	pF		
C _{I/O}	I/O pin capacitance	V _{OUT} = 0 V, f = 1.0 MHz		10	pF		

Notes to tables:

- (1) See the Operating Requirements for Altera Devices Data Sheet.
- (2) Minimum DC input voltage on I/O pins is –0.5 V and on 4 dedicated input pins is –0.3 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 7.0 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) Numbers in parentheses are for industrial-temperature-range devices.
- (4) V_{CC} must rise monotonically.
- (5) The POR time for all 7000S devices does not exceed 300 μs. The sufficient V_{CCINT} voltage level for POR is 4.5 V. The device is fully initialized within the POR time after V_{CCINT} reaches the sufficient POR voltage level.
- (6) 3.3-V I/O operation is not available for 44-pin packages.
- (7) The V_{CCISP} parameter applies only to MAX 7000S devices.
- (8) During in-system programming, the minimum DC input voltage is –0.3 V.
- (9) These values are specified under the MAX 7000 recommended operating conditions in Table 14 on page 26.
- (10) The parameter is measured with 50% of the outputs each sourcing the specified current. The I_{OH} parameter refers to high-level TTL or CMOS output current.
- (11) The parameter is measured with 50% of the outputs each sinking the specified current. The I_{OL} parameter refers to low-level TTL, PCI, or CMOS output current.
- (12) When the JTAG interface is enabled in MAX 7000S devices, the input leakage current on the JTAG pins is typically -60 uA.
- (13) Capacitance is measured at 25° C and is sample-tested only. The OE1 pin has a maximum capacitance of 20 pF.

Figure 11 shows the typical output drive characteristics of MAX 7000 devices.

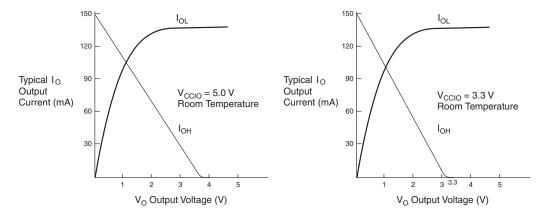


Figure 11. Output Drive Characteristics of 5.0-V MAX 7000 Devices

Timing Model

MAX 7000 device timing can be analyzed with the Altera software, with a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 12. MAX 7000 devices have fixed internal delays that enable the designer to determine the worst-case timing of any design. The Altera software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for a device-wide performance evaluation.

Symbol	Parameter	Conditions	Speed Grade					
			MAX 700	OE (-10P)	MAX 70	-		
			Min	Max	Min	Max		
t _{IN}	Input pad and buffer delay			0.5		1.0	ns	
t _{IO}	I/O input pad and buffer delay			0.5		1.0	ns	
t _{FIN}	Fast input delay	(2)		1.0		1.0	ns	
t _{SEXP}	Shared expander delay			5.0		5.0	ns	
t _{PEXP}	Parallel expander delay			0.8		0.8	ns	
t_{LAD}	Logic array delay			5.0		5.0	ns	
t _{LAC}	Logic control array delay			5.0		5.0	ns	
t _{IOE}	Internal output enable delay	(2)		2.0		2.0	ns	
t _{OD1}	Output buffer and pad delay Slow slew rate = off V _{CCIO} = 5.0 V	C1 = 35 pF		1.5		2.0	ns	
t _{OD2}	Output buffer and pad delay Slow slew rate = off V _{CCIO} = 3.3 V	C1 = 35 pF (7)		2.0		2.5	ns	
t _{OD3}	Output buffer and pad delay Slow slew rate = on V _{CCIO} = 5.0 V or 3.3 V	C1 = 35 pF (2)		5.5		6.0	ns	
t _{ZX1}	Output buffer enable delay Slow slew rate = off V _{CCIO} = 5.0 V	C1 = 35 pF		5.0		5.0	ns	
t _{ZX2}	Output buffer enable delay Slow slew rate = off V _{CCIO} = 3.3 V	C1 = 35 pF (7)		5.5		5.5	ns	
t _{ZX3}	Output buffer enable delay Slow slew rate = on V _{CCIO} = 5.0 V or 3.3 V	C1 = 35 pF (2)		9.0		9.0	ns	
t_{XZ}	Output buffer disable delay	C1 = 5 pF		5.0		5.0	ns	
t_{SU}	Register setup time		2.0		3.0		ns	
t_H	Register hold time		3.0		3.0		ns	
t _{FSU}	Register setup time of fast input	(2)	3.0		3.0		ns	
t_{FH}	Register hold time of fast input	(2)	0.5		0.5		ns	
t _{RD}	Register delay			2.0		1.0	ns	
t _{COMB}	Combinatorial delay			2.0		1.0	ns	
t _{IC}	Array clock delay			5.0		5.0	ns	
t_{EN}	Register enable time			5.0		5.0	ns	
t _{GLOB}	Global control delay			1.0		1.0	ns	
t _{PRE}	Register preset time			3.0		3.0	ns	
t _{CLR}	Register clear time			3.0		3.0	ns	
t_{PIA}	PIA delay			1.0		1.0	ns	
t _{LPA}	Low-power adder	(8)		11.0		11.0	ns	

Table 27. EPM7032S External Timing Parameters (Part 2 of 2) Note (1)											
Symbol	Parameter	Conditions				Speed	Grade	!			Unit
			-	5	-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
f _{ACNT}	Maximum internal array clock frequency	(4)	175.4		142.9		116.3		100.0		MHz
f _{MAX}	Maximum clock frequency	(5)	250.0		200.0		166.7		125.0		MHz

Table 2	8. EPM7032S Internal Tim	ing Parameter	s /	Note (1)							
Symbol	Parameter	Conditions	Speed Grade								Unit
			-5		-	6	-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	-
t _{IN}	Input pad and buffer delay			0.2		0.2		0.3		0.5	ns
t _{IO}	I/O input pad and buffer delay			0.2		0.2		0.3		0.5	ns
t _{FIN}	Fast input delay			2.2		2.1		2.5		1.0	ns
t _{SEXP}	Shared expander delay			3.1		3.8		4.6		5.0	ns
t _{PEXP}	Parallel expander delay			0.9		1.1		1.4		0.8	ns
t _{LAD}	Logic array delay			2.6		3.3		4.0		5.0	ns
t _{LAC}	Logic control array delay			2.5		3.3		4.0		5.0	ns
t _{IOE}	Internal output enable delay			0.7		0.8		1.0		2.0	ns
t _{OD1}	Output buffer and pad delay	C1 = 35 pF		0.2		0.3		0.4		1.5	ns
t _{OD2}	Output buffer and pad delay	C1 = 35 pF (6)		0.7		0.8		0.9		2.0	ns
t _{OD3}	Output buffer and pad delay	C1 = 35 pF		5.2		5.3		5.4		5.5	ns
t_{ZX1}	Output buffer enable delay	C1 = 35 pF		4.0		4.0		4.0		5.0	ns
t _{ZX2}	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		4.5		5.5	ns
t _{ZX3}	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		9.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		4.0		4.0		5.0	ns
t _{SU}	Register setup time		0.8		1.0		1.3		2.0		ns
t _H	Register hold time		1.7		2.0		2.5		3.0		ns
t _{FSU}	Register setup time of fast input		1.9		1.8		1.7		3.0		ns
t _{FH}	Register hold time of fast input		0.6		0.7		0.8		0.5		ns
t _{RD}	Register delay			1.2		1.6		1.9		2.0	ns
t _{COMB}	Combinatorial delay			0.9		1.1		1.4		2.0	ns
t _{IC}	Array clock delay			2.7		3.4		4.2		5.0	ns
t _{EN}	Register enable time			2.6		3.3		4.0		5.0	ns
t _{GLOB}	Global control delay			1.6		1.4		1.7		1.0	ns
t _{PRE}	Register preset time			2.0		2.4		3.0		3.0	ns
t _{CLR}	Register clear time			2.0		2.4		3.0		3.0	ns

Table 29. EPM7064S External Timing Parameters (Part 2 of 2) Note (1) Symbol Parameter Conditions Speed Grade Unit												
Symbol	Parameter	Conditions	Speed Grade									
			-5		-6		-7		-10			
			Min	Max	Min	Max	Min	Max	Min	Max		
t _{ACO1}	Array clock to output delay	C1 = 35 pF		5.4		6.7		7.5		10.0	ns	
t _{ACH}	Array clock high time		2.5		2.5		3.0		4.0		ns	
t _{ACL}	Array clock low time		2.5		2.5		3.0		4.0		ns	
t _{CPPW}	Minimum pulse width for clear and preset	(2)	2.5		2.5		3.0		4.0		ns	
t _{ODH}	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		1.0		ns	
t _{CNT}	Minimum global clock period			5.7		7.1		8.0		10.0	ns	
f _{CNT}	Maximum internal global clock frequency	(4)	175.4		140.8		125.0		100.0		MHz	
t _{ACNT}	Minimum array clock period			5.7		7.1		8.0		10.0	ns	
f _{ACNT}	Maximum internal array clock frequency	(4)	175.4		140.8		125.0		100.0		MHz	
f _{MAX}	Maximum clock frequency	(5)	250.0		200.0		166.7		125.0		MHz	

Table 3	O. EPM7064\$ Internal Tim	ing Parameters	(Part	1 of 2)	No	te (1)					
Symbol	Parameter	Conditions	Speed Grade								
			-5		-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
t _{IN}	Input pad and buffer delay			0.2		0.2		0.5		0.5	ns
t _{IO}	I/O input pad and buffer delay			0.2		0.2		0.5		0.5	ns
t _{FIN}	Fast input delay			2.2		2.6		1.0		1.0	ns
t _{SEXP}	Shared expander delay			3.1		3.8		4.0		5.0	ns
t_{PEXP}	Parallel expander delay			0.9		1.1		0.8		0.8	ns
t_{LAD}	Logic array delay			2.6		3.2		3.0		5.0	ns
t _{LAC}	Logic control array delay			2.5		3.2		3.0		5.0	ns
t _{IOE}	Internal output enable delay			0.7		0.8		2.0		2.0	ns
t _{OD1}	Output buffer and pad delay	C1 = 35 pF		0.2		0.3		2.0		1.5	ns
t _{OD2}	Output buffer and pad delay	C1 = 35 pF (6)		0.7		0.8		2.5		2.0	ns
t _{OD3}	Output buffer and pad delay	C1 = 35 pF		5.2		5.3		7.0		5.5	ns
t_{ZX1}	Output buffer enable delay	C1 = 35 pF		4.0		4.0		4.0		5.0	ns
t _{ZX2}	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		4.5		5.5	ns
t _{ZX3}	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		9.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		4.0		4.0		5.0	ns
t _{SU}	Register setup time		0.8		1.0		3.0		2.0		ns
t _H	Register hold time		1.7		2.0		2.0		3.0		ns

Symbol	Parameter	Conditions				Speed	Grade				Unit
			-5		-6		-7		-10		1
			Min	Max	Min	Max	Min	Max	Min	Max	
t _{FSU}	Register setup time of fast input		1.9		1.8		3.0		3.0		ns
t _{FH}	Register hold time of fast input		0.6		0.7		0.5		0.5		ns
t _{RD}	Register delay			1.2		1.6		1.0		2.0	ns
t _{COMB}	Combinatorial delay			0.9		1.0		1.0		2.0	ns
t _{IC}	Array clock delay			2.7		3.3		3.0		5.0	ns
t _{EN}	Register enable time			2.6		3.2		3.0		5.0	ns
t_{GLOB}	Global control delay			1.6		1.9		1.0		1.0	ns
t _{PRE}	Register preset time			2.0		2.4		2.0		3.0	ns
t _{CLR}	Register clear time			2.0		2.4		2.0		3.0	ns
t _{PIA}	PIA delay	(7)		1.1		1.3		1.0		1.0	ns
t_{LPA}	Low-power adder	(8)		12.0		11.0		10.0		11.0	ns

Notes to tables:

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The f_{MAX} values represent the highest frequency for pipelined data.
- (6) Operating conditions: $V_{CCIO} = 3.3 \text{ V} \pm 10\%$ for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{IC} , t_{EN} , t_{SEXP} , $\mathbf{t_{ACL}}$, and $\mathbf{t_{CPPW}}$ parameters for macrocells running in the low-power mode.

Table 3	Table 36. EPM7192S Internal Timing Parameters (Part 2 of 2)Note (1)											
Symbol	Parameter	Conditions			Unit							
				-7		-10		-15				
			Min	Max	Min	Max	Min	Max				
t _H	Register hold time		1.7		3.0		4.0		ns			
t _{FSU}	Register setup time of fast input		2.3		3.0		2.0		ns			
t _{FH}	Register hold time of fast input		0.7		0.5		1.0		ns			
t _{RD}	Register delay			1.4		2.0		1.0	ns			
t _{COMB}	Combinatorial delay			1.2		2.0		1.0	ns			
t_{IC}	Array clock delay			3.2		5.0		6.0	ns			
t _{EN}	Register enable time			3.1		5.0		6.0	ns			
t_{GLOB}	Global control delay			2.5		1.0		1.0	ns			
t _{PRE}	Register preset time			2.7		3.0		4.0	ns			
t _{CLR}	Register clear time			2.7		3.0		4.0	ns			
t _{PIA}	PIA delay	(7)		2.4		1.0		2.0	ns			
t_{LPA}	Low-power adder	(8)		10.0		11.0		13.0	ns			

Notes to tables:

- These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The f_{MAX} values represent the highest frequency for pipelined data.
- (6) Operating conditions: $V_{CCIO} = 3.3 \text{ V} \pm 10\%$ for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{IC} , t_{EN} , t_{SEXP} , $\mathbf{t_{ACL}}$, and $\mathbf{t_{CPPW}}$ parameters for macrocells running in the low-power mode.

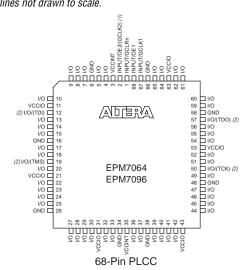
Tables 37 and 38 show the EPM7256S AC operating conditions.

Symbol	Parameter	Conditions	Speed Grade							
Oymboi	i arameter	Conditions	_	15	Unit					
			Min	Max	Min	IO Max	Min	Max	-	
4	Innut to non variatored output	C4 25 pF	IVIIII	7.5	IVIIII	10.0	IVIIII	15.0		
t _{PD1}	Input to non-registered output I/O input to non-registered output	C1 = 35 pF C1 = 35 pF		7.5		10.0		15.0	ns ns	
t _{SU}	Global clock setup time		3.9		7.0		11.0		ns	
t _H	Global clock hold time		0.0		0.0		0.0		ns	
t _{FSU}	Global clock setup time of fast input		3.0		3.0		3.0		ns	
t _{FH}	Global clock hold time of fast input		0.0		0.5		0.0		ns	
t _{CO1}	Global clock to output delay	C1 = 35 pF		4.7		5.0		8.0	ns	
t _{CH}	Global clock high time		3.0		4.0		5.0		ns	
t _{CL}	Global clock low time		3.0		4.0		5.0		ns	
t _{ASU}	Array clock setup time		0.8		2.0		4.0		ns	
t _{AH}	Array clock hold time		1.9		3.0		4.0		ns	
t _{ACO1}	Array clock to output delay	C1 = 35 pF		7.8		10.0		15.0	ns	
t _{ACH}	Array clock high time		3.0		4.0		6.0		ns	
t _{ACL}	Array clock low time		3.0		4.0		6.0		ns	
t _{CPPW}	Minimum pulse width for clear and preset	(2)	3.0		4.0		6.0		ns	
t _{ODH}	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		ns	
t _{CNT}	Minimum global clock period			7.8		10.0		13.0	ns	
f _{CNT}	Maximum internal global clock frequency	(4)	128.2		100.0		76.9		MHz	
t _{ACNT}	Minimum array clock period			7.8		10.0		13.0	ns	
f _{ACNT}	Maximum internal array clock frequency	(4)	128.2		100.0		76.9		MHz	
f _{MAX}	Maximum clock frequency	(5)	166.7		125.0		100.0		MHz	

Symbol	Parameter	Conditions	Speed Grade							
			-	7	7 -		-1	15		
			Min	Max	Min	Max	Min	Max		
t _{IN}	Input pad and buffer delay			0.3		0.5		2.0	ns	
t _{IO}	I/O input pad and buffer delay			0.3		0.5		2.0	ns	
t _{FIN}	Fast input delay			3.4		1.0		2.0	ns	
t _{SEXP}	Shared expander delay			3.9		5.0		8.0	ns	
t_{PEXP}	Parallel expander delay			1.1		0.8		1.0	ns	
t_{LAD}	Logic array delay			2.6		5.0		6.0	ns	
t _{LAC}	Logic control array delay			2.6		5.0		6.0	ns	
t _{IOE}	Internal output enable delay			0.8		2.0		3.0	ns	
t _{OD1}	Output buffer and pad delay	C1 = 35 pF		0.5		1.5		4.0	ns	
t _{OD2}	Output buffer and pad delay	C1 = 35 pF (6)		1.0		2.0		5.0	ns	
t _{OD3}	Output buffer and pad delay	C1 = 35 pF		5.5		5.5		8.0	ns	
t _{ZX1}	Output buffer enable delay	C1 = 35 pF		4.0		5.0		6.0	ns	
t _{ZX2}	Output buffer enable delay	C1 = 35 pF (6)		4.5		5.5		7.0	ns	
t _{ZX3}	Output buffer enable delay	C1 = 35 pF		9.0		9.0		10.0	ns	
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		5.0		6.0	ns	
t _{SU}	Register setup time		1.1		2.0		4.0		ns	
t _H	Register hold time		1.6		3.0		4.0		ns	
t _{FSU}	Register setup time of fast input		2.4		3.0		2.0		ns	
t _{FH}	Register hold time of fast input		0.6		0.5		1.0		ns	
t_{RD}	Register delay			1.1		2.0		1.0	ns	
t _{COMB}	Combinatorial delay			1.1		2.0		1.0	ns	
t _{IC}	Array clock delay			2.9		5.0		6.0	ns	
t_{EN}	Register enable time			2.6		5.0		6.0	ns	
t _{GLOB}	Global control delay			2.8		1.0		1.0	ns	
t _{PRE}	Register preset time			2.7		3.0		4.0	ns	
t _{CLR}	Register clear time			2.7		3.0		4.0	ns	
t _{PIA}	PIA delay	(7)		3.0		1.0		2.0	ns	
t _{LPA}	Low-power adder	(8)		10.0	İ	11.0		13.0	ns	

Figure 17. 68-Pin Package Pin-Out Diagram

Package outlines not drawn to scale.



Notes:

- The pin functions shown in parenthesis are only available in MAX 7000E and MAX 7000S devices.
- (2) JTAG ports are available in MAX 7000S devices only.





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